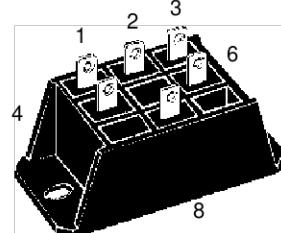
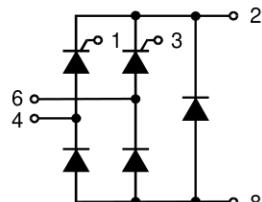


# Half Controlled Single Phase Rectifier Bridge with Freewheeling Diode

**I<sub>dAVM</sub> = 21 A**  
**V<sub>RRM</sub> = 800-1600 V**

V <sub>RSM</sub> V <sub>DSM</sub>	V <sub>RRM</sub> V <sub>DRM</sub>	Type
V	V	
900	800	VHF 15-08io5
1300	1200	VHF 15-12io5
1500	1400	VHF 15-14io5
1700	1600	VHF 15-16io5



Symbol	Test Conditions	Maximum Ratings		
I <sub>dAV</sub>	T <sub>K</sub> = 85°C, module	15	A	
I <sub>dAVM</sub> ①	module	21	A	
I <sub>FRMS</sub> , I <sub>TRMS</sub>	per leg	15	A	
I <sub>FSM</sub> , I <sub>TSM</sub>	T <sub>VJ</sub> = 45°C; V <sub>R</sub> = 0 V	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	190 210	A A
	T <sub>VJ</sub> = T <sub>VJM</sub> V <sub>R</sub> = 0 V	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	170 190	A A
I <sup>2</sup> t	T <sub>VJ</sub> = 45°C V <sub>R</sub> = 0 V	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	160 180	A <sup>2</sup> s A <sup>2</sup> s
	T <sub>VJ</sub> = T <sub>VJM</sub> V <sub>R</sub> = 0 V	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	140 145	A <sup>2</sup> s A <sup>2</sup> s
(di/dt) <sub>cr</sub>	T <sub>VJ</sub> = 125°C f = 50 Hz, t <sub>p</sub> = 200 μs V <sub>D</sub> = 2/3 V <sub>DRM</sub> I <sub>G</sub> = 0.3 A, di <sub>G</sub> /dt = 0.3 A/μs	repetitive, I <sub>T</sub> = 50 A  non repetitive, I <sub>T</sub> = 1/2 · I <sub>dAV</sub>	150 500	A/μs A/μs
(dv/dt) <sub>cr</sub>	T <sub>VJ</sub> = T <sub>VJM</sub> ; V <sub>DR</sub> = 2/3 V <sub>DRM</sub> R <sub>GK</sub> = ∞; method 1 (linear voltage rise)		1000	V/μs
V <sub>RGM</sub>			10	V
P <sub>GM</sub>	T <sub>VJ</sub> = T <sub>VJM</sub> I <sub>T</sub> = I <sub>TAVM</sub>	t <sub>p</sub> = 30 μs t <sub>p</sub> = 500 μs t <sub>p</sub> = 10 ms	≤ 10 ≤ 5 ≤ 1 0.5	W W W W
P <sub>GAVM</sub>			-40...+125 125 -40...+125	°C °C °C
T <sub>VJ</sub>			-40...+125	°C
T <sub>VJM</sub>			125	°C
T <sub>stg</sub>			-40...+125	°C
V <sub>ISOL</sub>	50/60 Hz, RMS I <sub>ISOL</sub> ≤ 1 mA	t = 1 min t = 1 s	3000 3600	V~ V~
M <sub>d</sub>	Mounting torque	(M5) (10-32 UNF)	2-2.5 18-22	Nm lb.in.
Weight			50	g

Data according to IEC 60747 and refer to a single thyristor/diode unless otherwise stated.

① for resistive load

IXYS reserves the right to change limits, test conditions and dimensions.

## Features

- Package with DCB ceramic base plate
- Isolation voltage 3600 V~
- Planar passivated chips
- 1/4" fast-on terminals
- UL registered E 72873

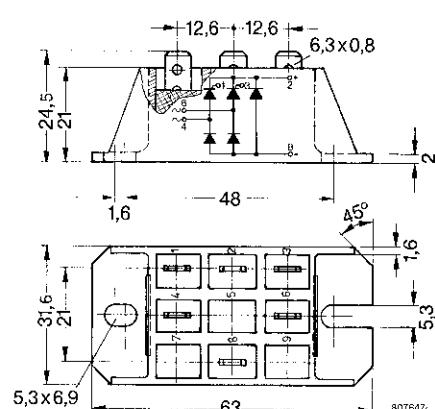
## Applications

- Supply for DC power equipment
- DC motor control

## Advantages

- Easy to mount with two screws
- Space and weight savings
- Improved temperature and power cycling

## Dimensions in mm (1 mm = 0.0394")



Symbol	Test Conditions	Characteristic Values		
$I_R, I_D$	$V_R = V_{RRM}; V_D = V_{DRM}$ $T_{VJ} = T_{VJM}$ $T_{VJ} = 25^\circ C$	≤ 5	mA	
		≤ 0.3	mA	
$V_T, V_F$	$I_T, I_F = 45 A; T_{VJ} = 25^\circ C$	≤ 2.8	V	
$V_{TO}$	For power-loss calculations only ( $T_{VJ} = 125^\circ C$ )	1.0	V	
$r_T$		40	$m\Omega$	
$V_{GT}$	$V_D = 6 V;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$	≤ 1.0	V	
$I_{GT}$	$V_D = 6 V;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$ $T_{VJ} = 125^\circ C$	≤ 65	mA	
		≤ 80	mA	
		≤ 50	mA	
$V_{GD}$	$T_{VJ} = T_{VJM};$ $T_{VJ} = T_{VJM};$	$V_D = 2/3 V_{DRM}$	≤ 0.2	V
$I_{GD}$		$V_D = 2/3 V_{DRM}$	≤ 5	mA
$I_L$	$I_G = 0.3 A; t_g = 30 \mu s;$ $di_g/dt = 0.3 A/\mu s;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$ $T_{VJ} = 125^\circ C$	≤ 150	mA	
		≤ 200	mA	
		≤ 100	mA	
$I_H$	$T_{VJ} = 25^\circ C; V_D = 6 V; R_{GK} = \infty$	≤ 100	mA	
$t_{gd}$	$T_{VJ} = 25^\circ C; V_D = 1/2 V_{DRM}$ $I_G = 0.3 A; di_g/dt = 0.3 A/\mu s$	≤ 2	$\mu s$	
$t_q$	$T_{VJ} = 125^\circ C, I_T = 15 A, t_p = 300 \mu s, V_R = 100 V$	typ.	150	$\mu s$
$Q_r$	$di/dt = -10 A/\mu s, dv/dt = 20 V/\mu s, V_D = 2/3 V_{DRM}$	75	$\mu C$	
$R_{thJC}$	per thyristor (diode); DC current	2.4	K/W	
	per module	0.6	K/W	
$R_{thJK}$	per thyristor (diode); DC current	3.0	K/W	
	per module	0.75	K/W	
$d_s$	Creepage distance on surface	12.6	mm	
$d_a$	Creepage distance in air	6.3	mm	
$a$	Max. allowable acceleration	50	$m/s^2$	

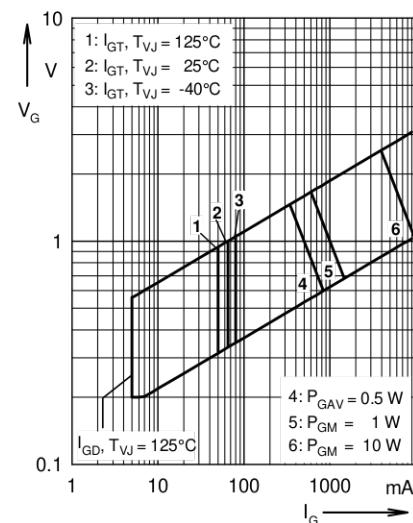
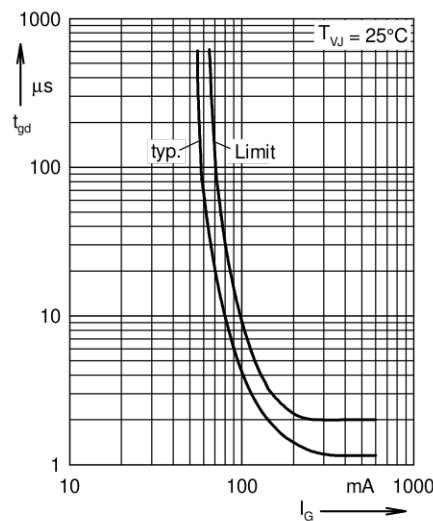


Fig. 1 Gate trigger range

Fig. 2 Gate controlled delay time  $t_{gd}$

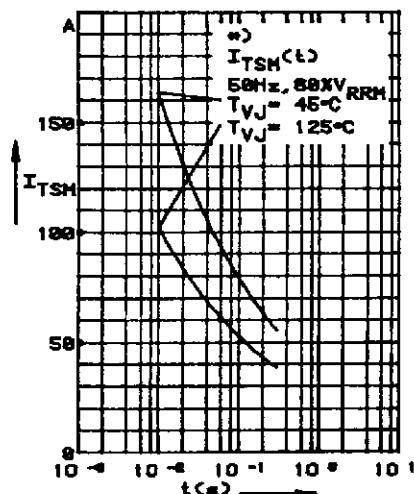


Fig. 3 Surge overload current per chip  
 $I_{TSM}$ : Crest value,  $t$ : duration

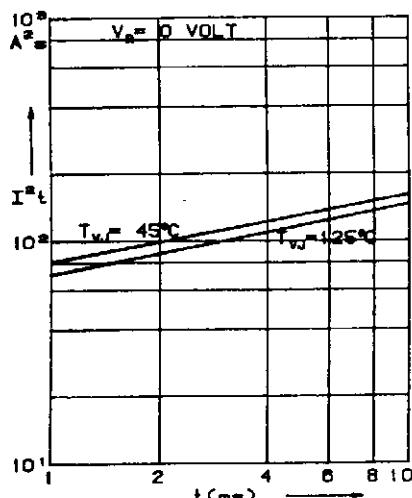


Fig. 4  $I^2t$  versus time (1-10 ms)  
per chip

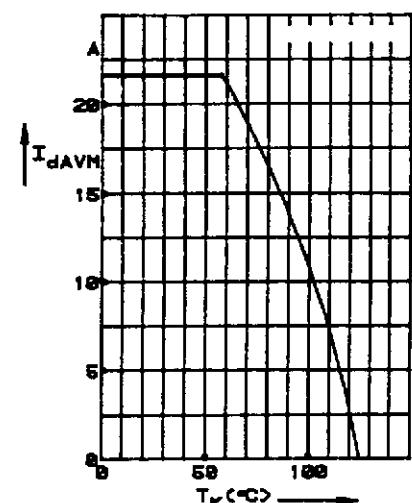


Fig. 5 Max. forward current at  
heatsink temperature

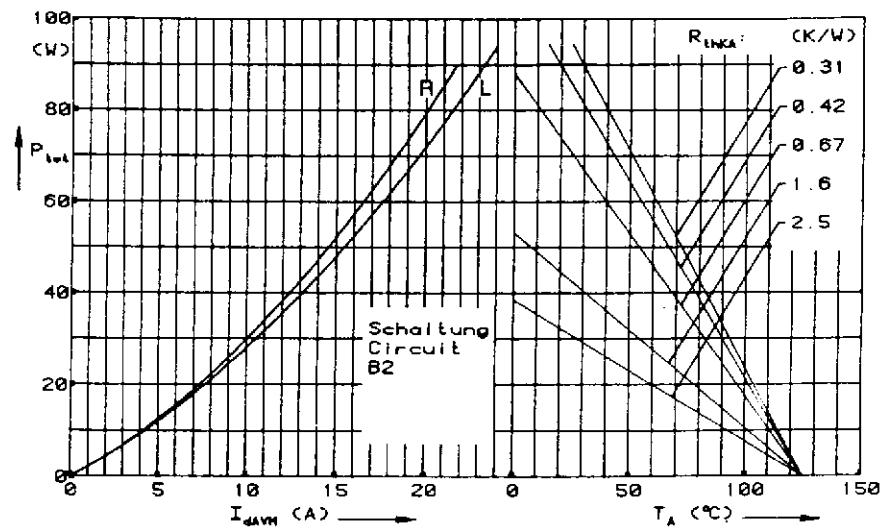


Fig. 6 Power dissipation versus direct output current and ambient temperature

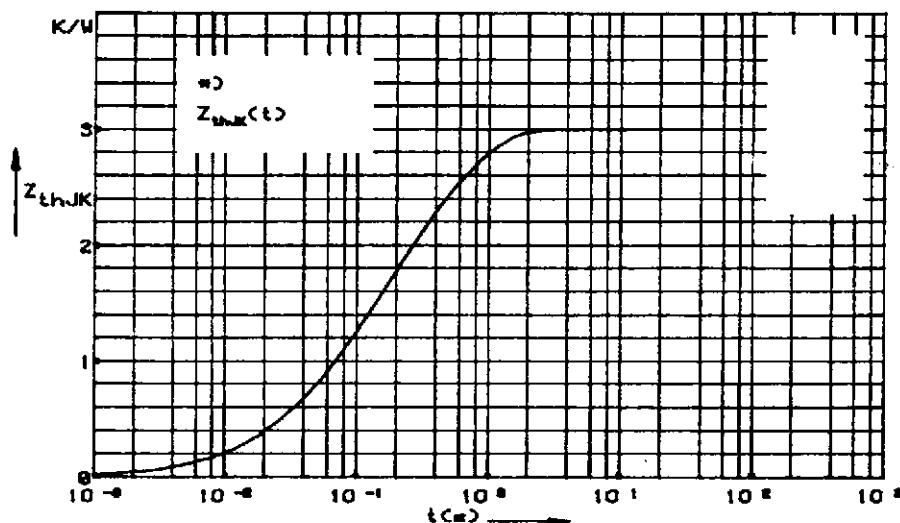


Fig. 7 Transient thermal impedance junction to heatsink per chip

Constants for  $Z_{thJK}$  calculation:

i	$R_{thi}$ (K/W)	$t_i$ (s)
1	0.34	0.0344
2	1.16	0.12
3	1.5	0.5